II. AMENDMENTS TO THE CLAIMS

This listing of claims replaces all prior listings, or versions, of claims.

1. (Currently Amended) A method for generating a process aid on a wafer, the method comprising ~~the steps of~~:

entering a process technology and a process aid type to be built into a program;

reading technology design rules and process aid parameters for the process aid type into the program;

accessing a process aid instruction file to attain instructions for building the process aid; and

building the process aid ~~in~~ on the wafer using the instructions based on the technology design rules and the process aid parameters, the process aid being different than a kerf on the wafer.

2. (Original) The method of claim 1, wherein the building step includes building the process aid in one of a kerf and a sacrificial die on the wafer.

3. (Original) The method of claim 1, wherein the instructions include scheme code.

4. (Original) The method of claim 1, further comprising the step of documenting the process aid.

5. (Original) The method of claim 4, wherein the documentation includes process aid

location.

6. (Original) The method of claim 1, further comprising at least one of the steps of verifying the process aid against production data and testing the process aid.

7. (Original) The method of claim 1, further comprising the step of rerunning the step of building.

8. (Currently Amended) A system for generating a process aid on a wafer, the system comprising:

means for entering a process technology and a process aid type into a program;

means for reading technology design rules and process aid parameters for the process aid into the program;

means for accessing a process aid instruction file to attain instructions for building the process aid; and

means for building the process aid on the wafer using the instructions based on the technology design rules and process aid parameters, the process aid being different than a kerf on the wafer.

9. (Original) The system of claim 8, wherein the process aid is one of an electrical device and an optical device.

10. (Original) The system of claim 8, wherein the instructions include scheme code.

11. (Original) The system of claim 8, further comprising means for documenting the process aid.

12. (Original) The system of claim 11, wherein the documentation includes process aid location.

13. (Original) The system of claim 8, further comprising means for verifying the process aid against production data.

14. (Original) The system of claim 8, further comprising means for testing the process aid.

15. (Currently Amended) A computer program product comprising a computer useable medium having computer readable program code embodied therein for generating a process aid on a wafer, the program product comprising:

program code configured to allow entering a process technology and the process aid type;

program code configured to read technology design rules and process aid parameters for the process aid;

program code configured to access a process aid instruction file to attain instructions for building the process aid; and

program code configured to build the process aid on the wafer using the instructions based on the technology design rules and process aid parameters, the process

aid being different than a kerf on the wafer.

16. (Original) The program product of claim 15, wherein the process aid is one of an electrical device and an optical device.

17. (Original) The program product of claim 15, wherein the instructions include scheme code.

18. (Original) The program product of claim 15, further comprising program code configured to document the process aid.

19. (Original) The program product of claim 15, further comprising program code configured to verify the process aid against production data.

20. (Original) The program product of claim 15, further comprising program code configured to test the process aid.